Fundamentals of Optoelectronic Materials and Devices

Topic:Chemical vapor deposition (CVD)

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Four wafer-fabrication operations

Layering

-Add metal, insulator, semiconductor thin layers onto the wafer surface



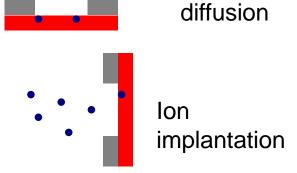
Patterning

-form pattern by removing selected portions of added surface layers



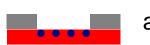
Doping

-incorporate dopants into a wafer



Heat treatment

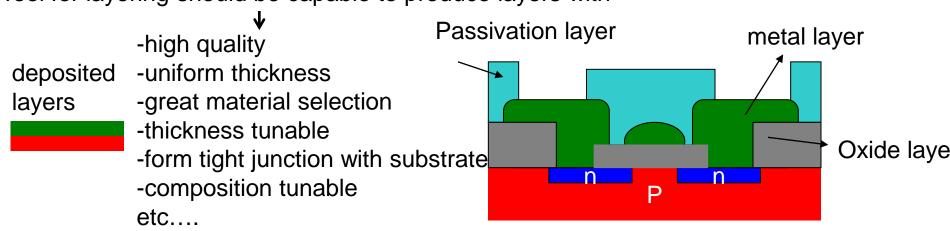
-remove contaminates, repair crystal structure of treated wafers



annealing

Layering

Tool for layering should be capable to produce layers with



Various layering methods were developed to layer a thin film on a wafer

Materials

-Metal, oxide, and semiconductor

Today's lecture references

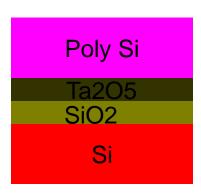
- Hugh O. Pierson, "Handbook of Chemical Vapor Deposition Principles, Technology and Applications, Noyes Publications
- Hitchman, M.L. and K.F. Jensen,
 "Chemical Vapor Deposition principles and applications," ed., Academic Press,
 San Diego, USA, 1993

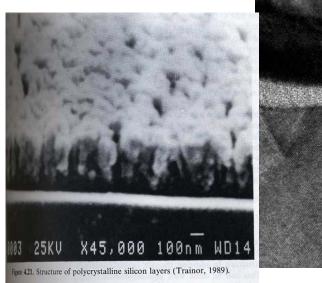
Chemical Vapor Deposition (CVD)

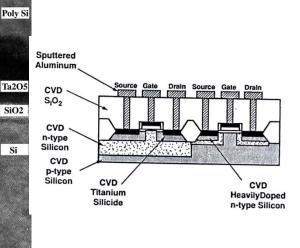
- A process can be used to produce thin solid films from gaseous reactants (so-called precursors) via chemical reactions – the most important thin-film deposition process.
- CVD can be extendedly used to produce ultra-fine (nano-sized) particles, fibers, foams, and powders.

CVD can be used to almost any kinds, any shape, and any size

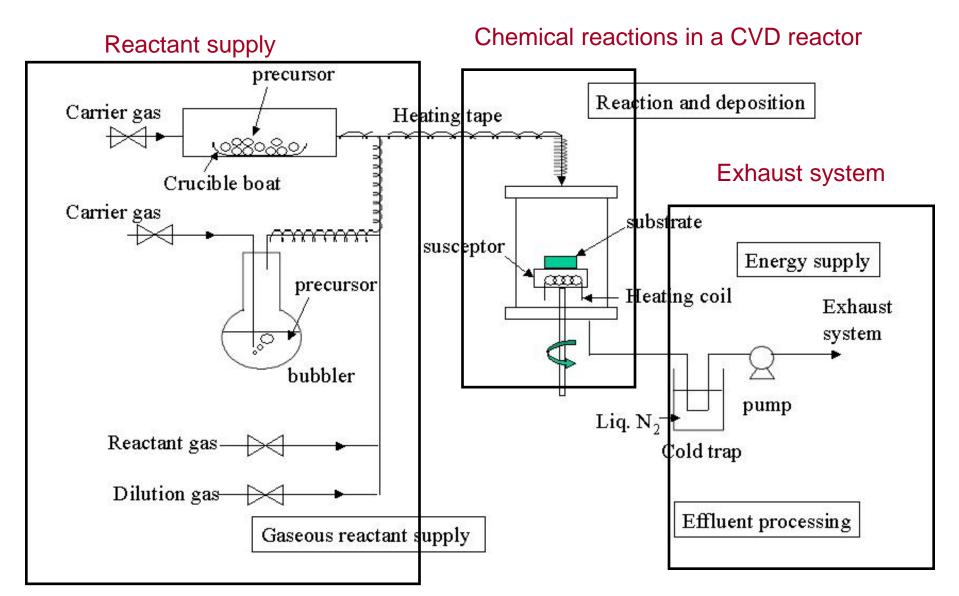
of materials with precise control,





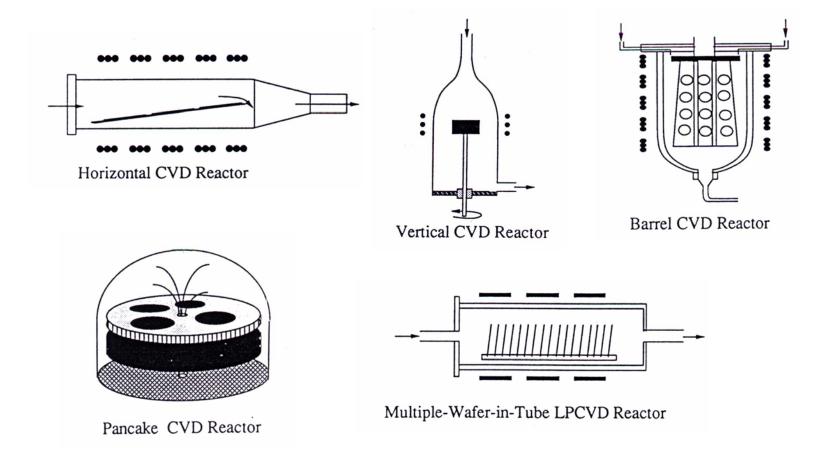


A Typical CVD Apparatus



Classification of CVD reactors

By reactor configuration:



CVD applications in chip fabrication

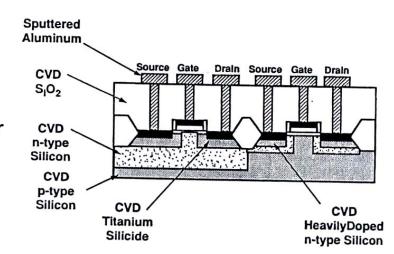
Electrical insulator

Silicon dioxide (SiO2)

- -Insulator, diffusion mask, ion-implantation mask, passivation against abrasion, schatches and the penetration of impurities and moisture *Silicon nitride*
- -Hard, scratch-resistant, excellent diffusion barrier for sodium and water to avoid corrosion

Semiconductors

Silicon, III-V and II-VI semiconductors

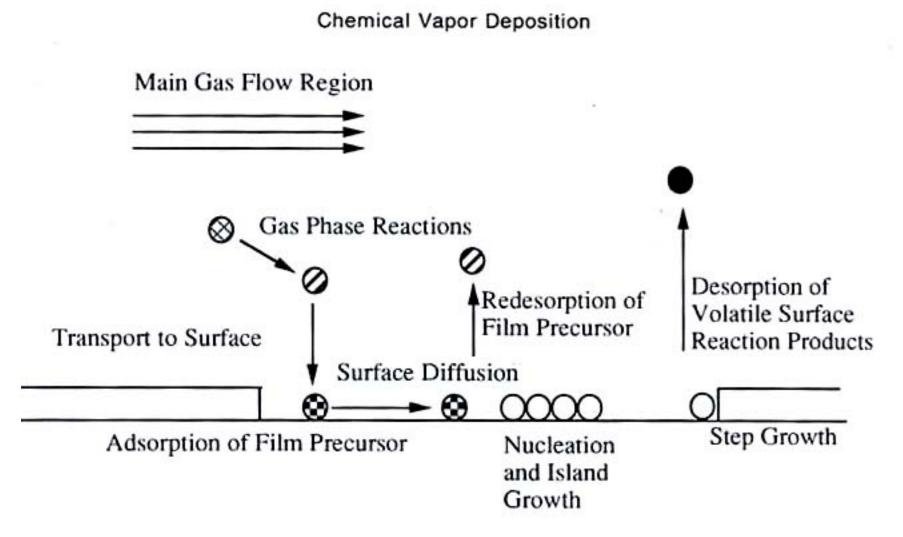


Electrical conductor for interconnection

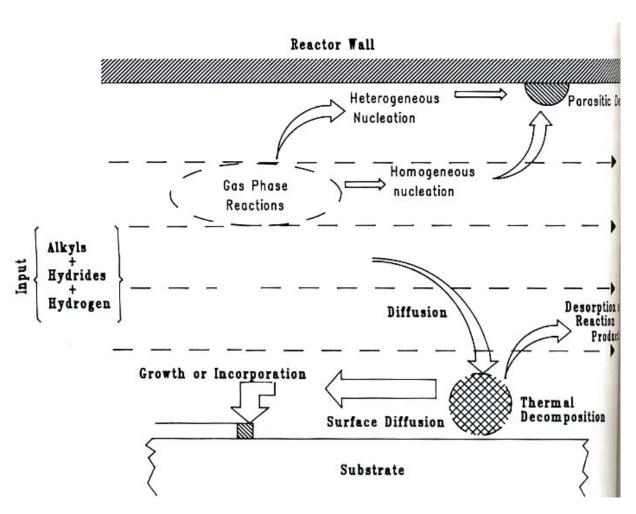
MoSi2, TiSi2, WSi2, TaSi2, and CoSi2

-Low resistivity, thermal stability, diffusion barrier, mitigation of the electromigration

Scheme of CVD transport and reaction processes



Film growth from chemical reactions in a CVD



Chemistry of CVD

Reactions can occur in either gas-phase and surface, leading to the formation of film precursors and byproducts

Types of reactions

-Pyrolysis, reduction, oxidation, hydrolysis, nitridation, carbidization, diproportionation

Reaction decomposition mechanism

- Gas-phase chemistry
- Surface chemistry

CVD precursors

general characteristics preferred:

- stability at room temperature not to react before being transported to reaction zone, easy storage and transfer
- 2. sufficient volatility at low temperatures convenient for transportation to reaction zone
- 3. capability of being produced in a high degree of purity to avoid introducing contaminants
- ability to react without producing unwanted side products to avoid low volatility, toxic side products
- 5. cost effective enough

Common CVD precursors

halides:

```
{F, Cl, Br, I} + more electropositive elements → {AlBr<sub>3</sub>, AlCl<sub>3</sub>, BCl<sub>3</sub>, BF<sub>3</sub>, CCl<sub>4</sub>, CF<sub>4</sub>, CrCl<sub>2</sub>, SiCl<sub>4</sub>, TiCl<sub>4</sub>, WF<sub>6</sub>, ZrBr<sub>4</sub>, ZrCl<sub>4</sub>…}
```

metal-organics: (reactive, volatile, moisture sensitive, low decomposition temperatures, not restricted to metals)

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M {in IIa, IIb, IIIa, IVa, Va, VIa} + one or more carbon (oxygen) atoms of an organic hydrocarbon groups (alkyls: -CH_3, - C_2H_5, ...; aryls: -C_6H_5, ...; acetylacetonates: -OC_5H_8O-, ...)
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```
(CH_3)_3AI, (C_2H_5)_2B, (CH_3)_2Cd, (C_6H_5)_2Be, Ca(C_5H_8O_2)_2 ...
```

metal carbonyls:

```
-(CO)- + transition metals with partially filled d-shell →
```

3d : Sc, Ti, V, Cr, Mn, Fe, Co, Ni

4d: Y, Zr, Nb, Mo, Tc, Ru, Rh, Pd, Ag

5d: Hf, Ta, W, Re, Os, Ir, Pt, Au

```
mononuclear, M(CO)_x: Cr(CO)_6, Fe(CO)_5, Ni(CO)_4, W(CO)_6 dinuclear, M_2(CO)_x: Mn_2(CO)_{12}, Fe_2(CO)_9, Co_2(CO)_8 polynuclear: Fe_3(CO)_{12}, Co_4(CO)_{12} metal carbonyl complexes: Mn(CO)CI, CoNO(CO)_3
```

hydrides:

```
H_2 + \{IIIa,IVa,Va,VIa\} \rightarrow AsH_3, B_2H_6, SiH_4, NH_3, ...
```

Chemistry of CVD, often involved reactions

Pyrolysis (thermal decomposition): Carbidization:

hydrocarbon : $CH_4(g) \rightarrow C(s) + 2 H_2(g)$

 $TiCl_4(g) + CH_4(g) \rightarrow TiC(s) + 4 HCl(g)$

hydride : $SiH_4(g) \rightarrow Si(s) + 2H_2(g)$

 $TiCl_4(g) + C(s) + 2 H_2(g) \rightarrow TiC(s) + 4 HCl(g)$

carbonyl : $Ni(CO)_4(g) \rightarrow Ni(s) + 4 CO(g)$

metal-organics : $CH_3SiCl_3(g) \rightarrow SiC(s) + 3 HCl(g)$ **Disproportionation:**

halide: $WF_6(g) \rightarrow W(s) + 3 F_2(g)$

 $2 \operatorname{Gel}_2(g) \rightarrow \operatorname{Ge}(s) + \operatorname{Gel}_4(g)$

Reduction:

hydrogen : WF₆(g) + 3 H₂(g) \rightarrow W(s) + 6 HF(g)

hydride : $(CH_3)_3Ga(g) + AsH_3(g) \rightarrow GaAs(s) + 3 CH_4(g)$

metal : $Til_4(g) + 2 Zn(s) \rightarrow Ti(s) + 2 Znl_2(g)$

Oxidation:

 $SiH_4(g) + O_2(g) \rightarrow SiO_2(s) + 2 H_2(g)$

 $SiH_4(g) + 4 N_2O(g) \rightarrow SiO_2(s) + 4 N_2(g) + 2 H_2O(g)$

Hydrolysis:

 $SiCl_4(g) + 2 CO_2(g) + 2 H_2(g) \rightarrow SiO_2(s) + 4 HCl(g) + 2 CO(g)$

 $Al_2Cl_6(g) + 3 H_2O(g) \rightarrow Al_2O_3(s) + 6 HCl(g)$

Nitridation:

 $3 \text{ SiH}_4(g) + 4 \text{ NH}_3(g) \rightarrow \text{Si}_3\text{N}_4(s) + 12 \text{ H}_2(g)$

 $SiH_4(g) + 2 N_2(g) \rightarrow Si_3N_4(s) + 6 H_2(g)$

Detailed decomposition mechanism: Silane chemistry

Porolysis of SiH4 is extremely complex, having 27 reactions, with 120 elementary reactions has been proposed.

Some examples are as follows:

Initial decomposition reaction of SiH4

SiH4 → SiH2 + H2 (elimination of H2)

Homogeneous decomposition

SiH2 + H2 → SiH4 (reformation of silane)

SiH2 + SiH4 → Si2H6 (insert itself into silane)

SiH2 + Si2H6 → Si3H8 (insert itself into disilane)

- Careful temperature and pressure control are critical to lead to expected reactions

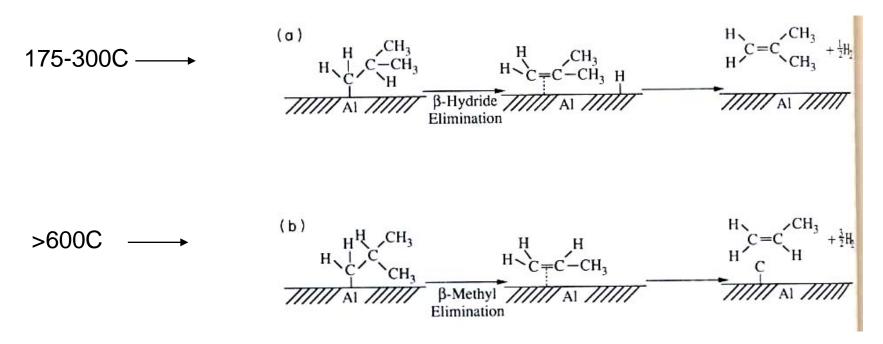
Surface reactions: silane decomposition

SiH4 (g) + s → H + SiH3
SiH3 + s → H + SiH2
2SiH2 → H2(g) + 2SiH
2SiH → H2(g) + 2s + Si film
2H → H2(g) + 2s

S: vancant sites and underlining d

Surface reactions of adsorbed alkyl aluminum compounds

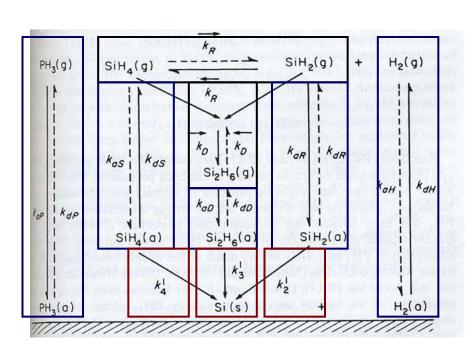
Using triisobutylaluminum as a precursor to deposit aluminum film



- -Low temperature (175-300C), high purity AI film was formed because of β-hydride elimination reactions dominate.
- -High temperature (>600C), carbon incorporation in aluminum film because of β-Methyl elimination reactions dominate

An example: In-situ phosphorus-doped

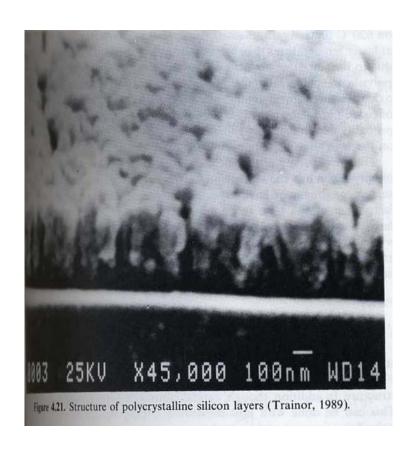
polycrystalline Si
Precursors: SiH4+PH3/N2 Overall process: SiH4+xPH3/N2 → SiPx + xN2 + (1.5x+2)H2



Growth reactions

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Gas-phase reactions:
           \mathbf{k}_{\mathsf{R}}
SiH4(g) \rightarrow SiH2(g) + H2(g)
                          \mathbf{k}_{\mathsf{D}}
SiH4(g) + SiH2(g) \rightarrow Si2H6(g)
                          K_D
Adsorption equilibria
           kas
SiH4(g) \rightarrow SiH4(a)
           KdS
           kaR
SiH2(g) \rightarrow SiH2(a)
           KdR
             kaD
Si2H6(g) \rightarrow Si2H6(a)
          KaPKdD
PH3(g) \rightarrow PH3(a)
        kaHkdP
H2(g)\rightarrow H2(a)
                                Hietchman p 201
         KdH
```

Polycrystalline silicon layer

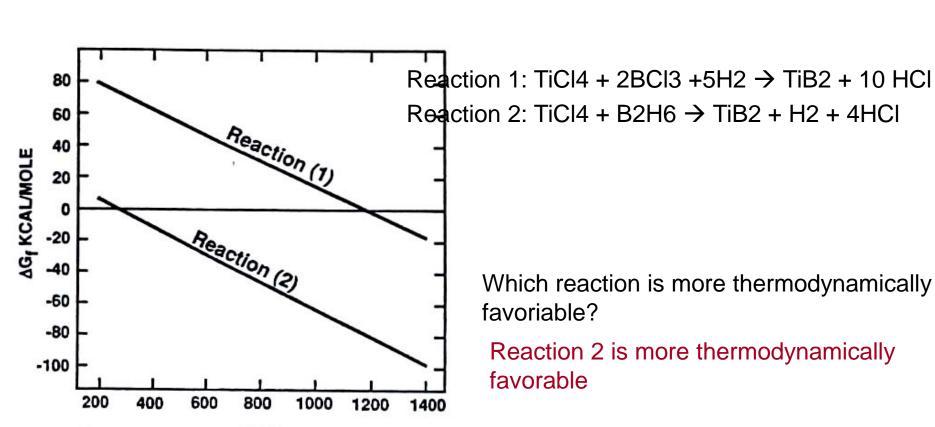


Thermodynamics of CVD

 $\Delta Gr = \Delta Gf + RT InQ$

ТК

Temperature is raised, Δ Gr more negative, and the reaction proceeds.

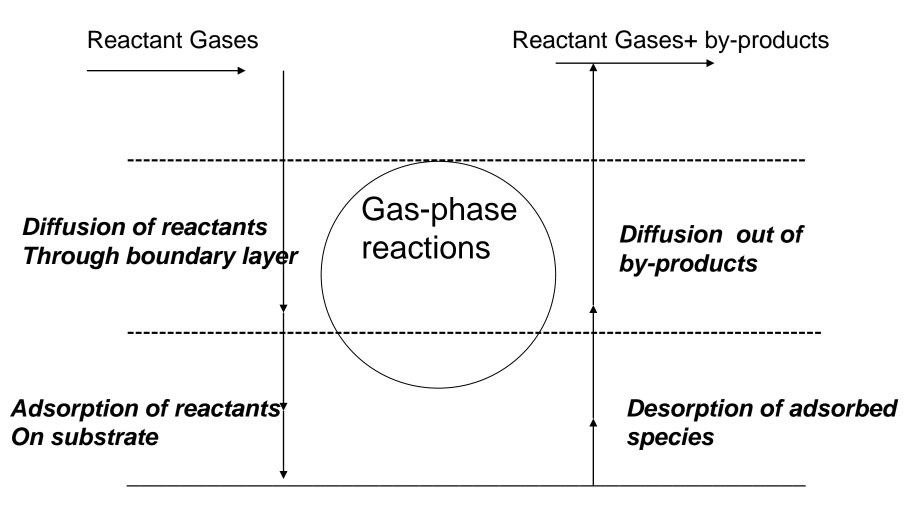


Pierson P22

Kinetics and Mass transport mechanism

- Deposition sequence
- Boundary layer
- Rate determining steps

Processes contributing to CVD growth

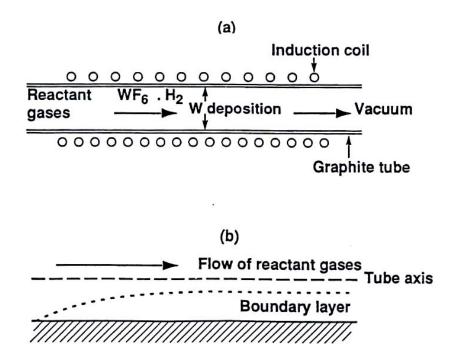


Chemical reaction on substrate

Substrate

Boundary layer

Reaction: WF6+3H2 →W+6HF



$$D = \sqrt{\frac{x}{R_e}} \qquad \text{Re} = \frac{\rho u_x}{\mu}$$

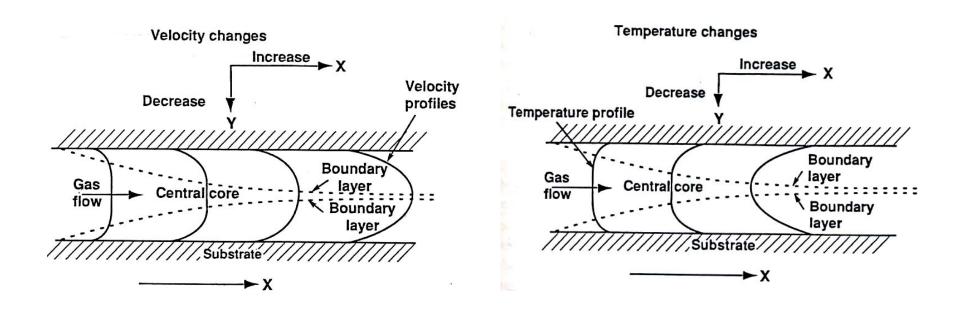
ρ= mass density
 u = flow density
 x = distance from inlet in flow direction
 μ= viscosity

D
$$\alpha$$
 x^{1/2} and $u_x^{-1/2}$ $u_x \downarrow \rightarrow D \uparrow$

- -Boundary layer: the region in which the flow velocity changes from zero at the wall to the same as the bulk gas speed
- -The thickness of the boundary layer increases with lowered gas flow velocity and with farer the distance from the tube inlet

Pierson p28

Velocity and temperature distribution profile



- -A steep velocity gradient is noticeable when x is larger
- -surface is the hottest
- -The shape distribution curve is similar to that of velocity

Reactant Gas is inverse proportional to x

Rate limiting Steps of a CVD reaction

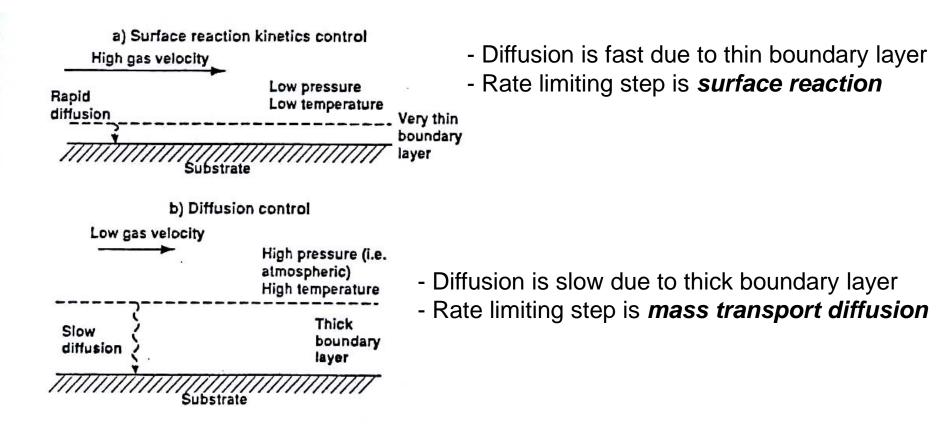
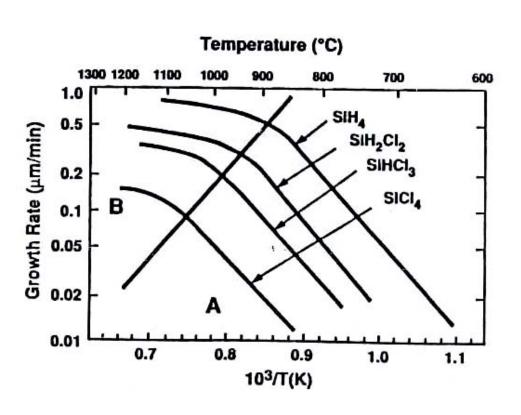


Figure 8. Rate Limiting Steps in a CVD Reaction

T(K) vs growth rate for silicon deposition using various precursors



Area A: lower temperature

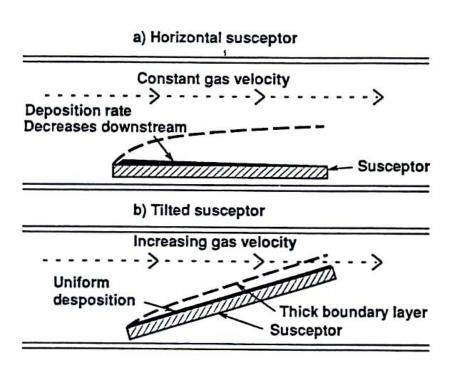
*Rate limiting step: (RLS)

growth rate is low So, RLS is surface reaction

Area B: higher temperature *Rate limiting step:

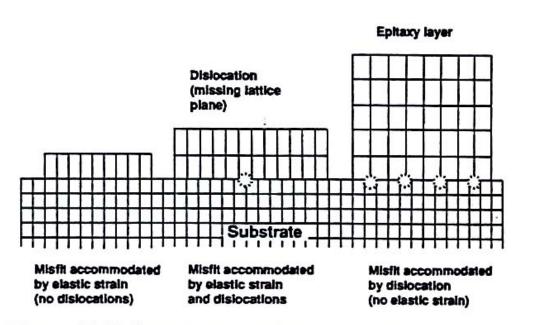
growth rate is high So, RLS is mass transport diffusion

Control of deposition uniformity in a tubular reactor



- -Deposition rate decreases downstream because of thicker boundary layer along the tube
- -Tilted susceptor makes boundary layers thiner because the increase of velocity from constriction of the flow → make the deposition layer more uniform

Deposition mechanism - Epitaxy



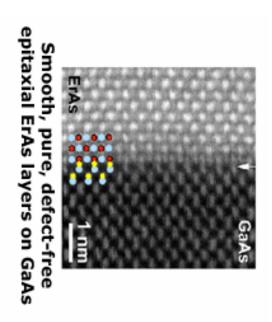


Figure 11. Epitaxy Accommodations of Lattice Mismatch

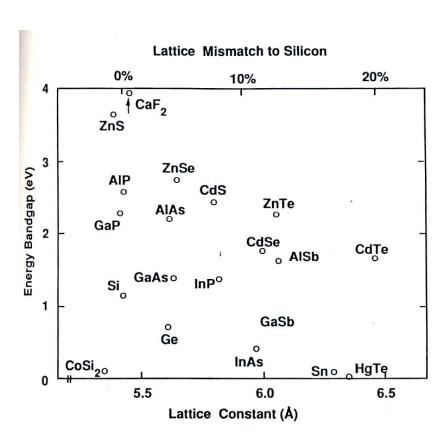
Defined as the growth of a crystalline film on a crystalline substrate

- -Homoepitaxy deposited materials are the same as substrate
- -Heteroepitaxy -

different

-Lattice mismatch of deposited materials with substrate Pierson p 38 needs to be small

Bandgap and lattice constant of semiconductor



Lattice mismatch larger than 8% is unlikely for deposited materials epitaxially growth on corresponding substrate

Pierson p39

Nucleation and growth modes

e de	Surface Coverage		
	θ < 1 mI	1 ml < θ < 2 ml	2 ml < θ
(a)	III Ministra		
(b)			
(c)			

Hitchman p37

Three-dimensional island growth-Volmer-Weber growth

film atoms are more strongly bound to each other than to the substrate (Si on SiO2, metals on insulators)

Layer-Plus-island growth-Stranski-Kastanov growth

Combination of two modes

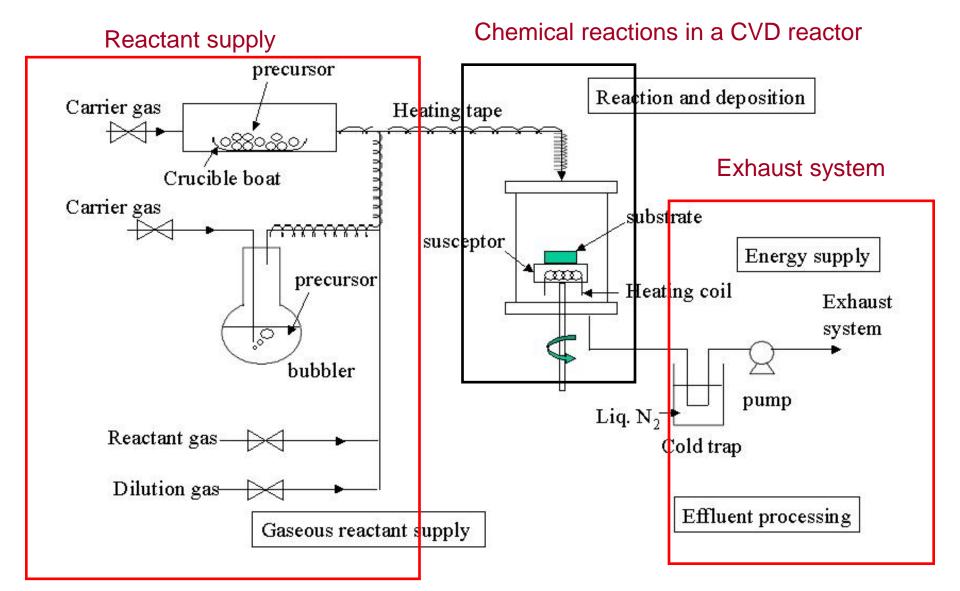
Layer-by-layer-Franck-van der Merwe growth

Film atoms are equally or less strongly bonded to each other than to the substrate (silicon on silicon, homoepitaxy

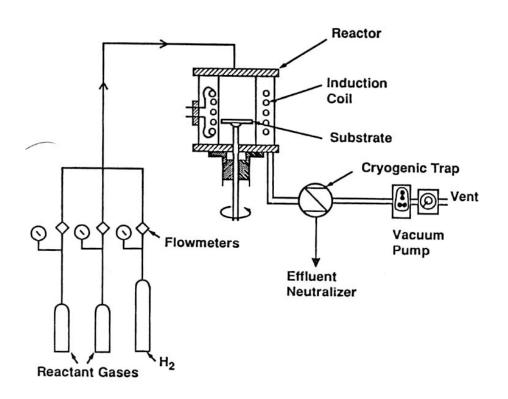
CVD Processes and Equipment

- Reactant supply
- Reactor types:
- -thermal CVD: hot and cold wall reactors
- -plasma CVD
- -MOCVD
- -laser CVD
- Exhaust and by-product disposal

A Typical CVD Apparatus



Reactant supply – gas precursor transport



A gas precursor tank



- Flowmeters to control the transport rate
- Carrier gas like H2 or N2 or O2 is often used

Reactant supply – liquid and solid precursor transport

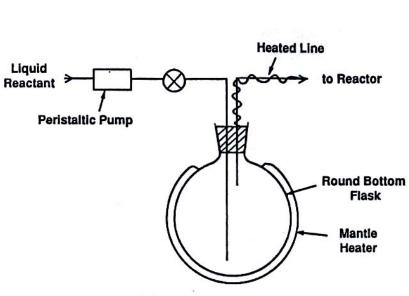
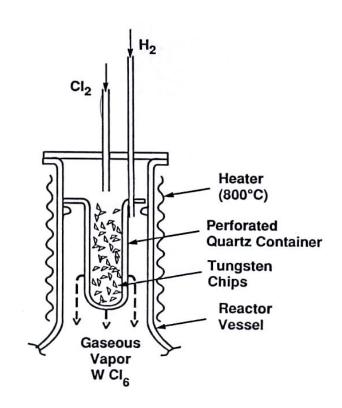
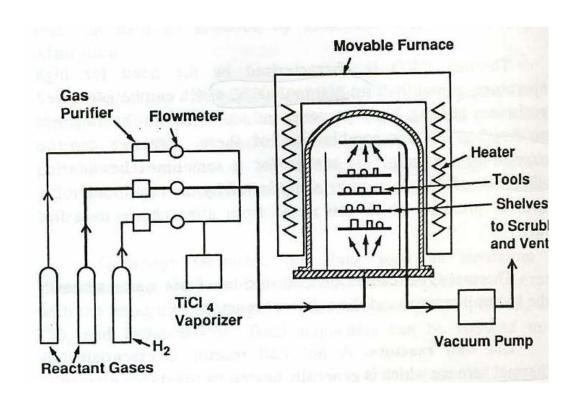


Figure 3. Vaporizer for Liquid Reactant



 $W(s) + 3 Cl2(g) \rightarrow WCl6(g) 800 oC$ deposition step: $WCl6(g) + 3 H2(g) \rightarrow W(s) + 6 HCl(g)$ at 800-1200 oC

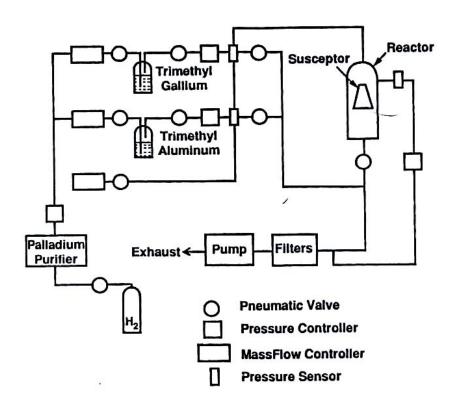
Thermal CVD- hot wall reactor



- Isothermal furnace
- Great temperature control
- Deposition occurs everywhere (clean is inconvenient)

Metallo-Organic CVD (MOCVD)

A MOCVD system

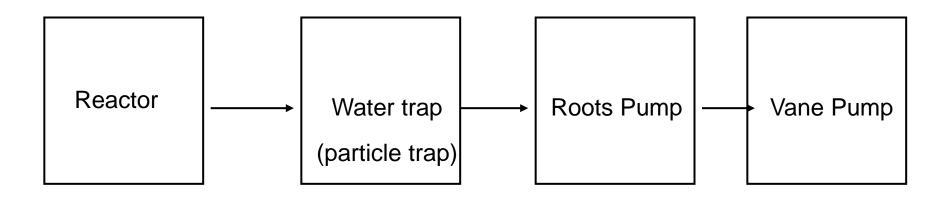


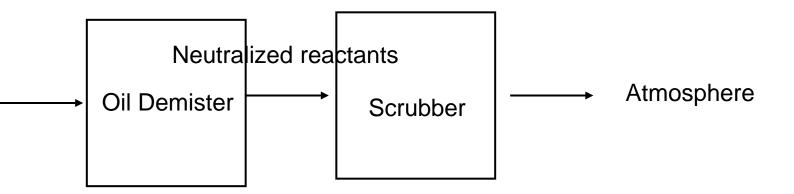
Alkyls or aryls substitute:

Acetylacetonates (乙酰丙酮基)

- A CVD system utilizes metallo-organic compounds as precursors.

Exhaust system



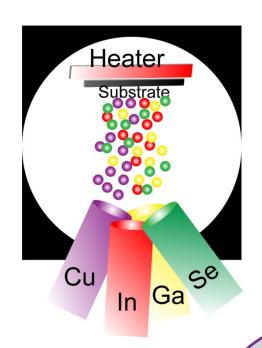


CVD precursors: toxic, lethal, and pyrophoric



Vacuum-based film deposition







TIME-CONSUMING

EXPENSIVE

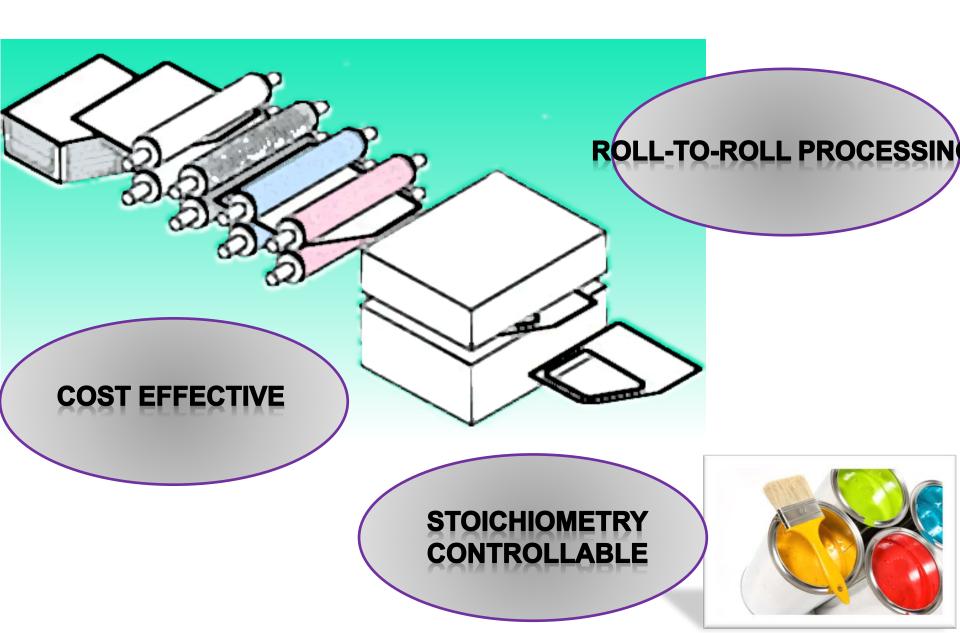
LOW THROUGHPU

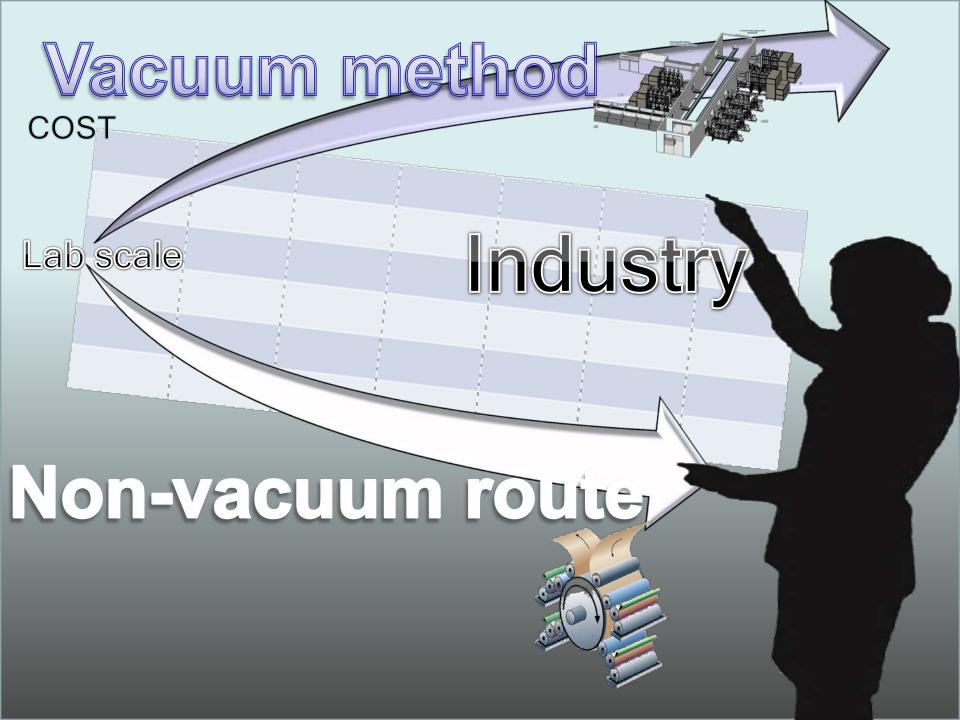
DIFFICULT TO CONTROL
STOICHIOMETRY
OVER LARGE AREAS

POOR MATERIALS UTILIZATION (30-50%)



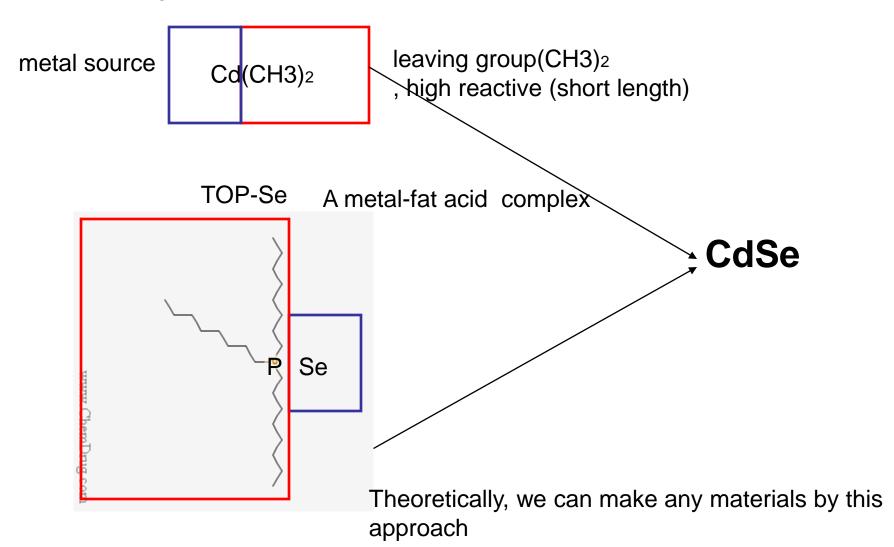
Non-Vacuum Processing



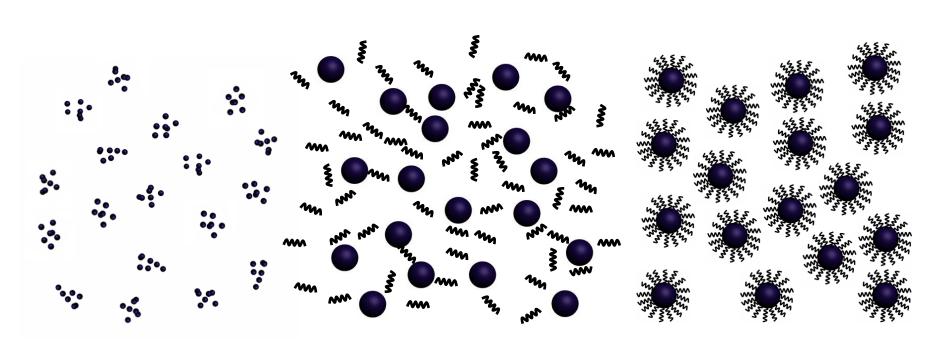


Bottom-up material synthesis

Organic metallic compound

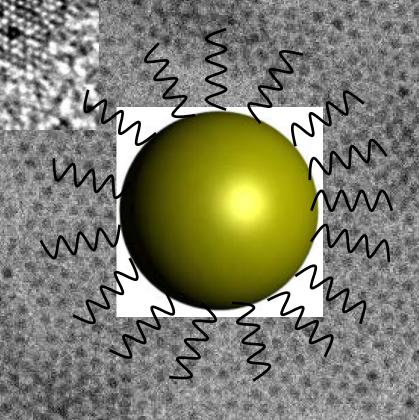


Bottom-up material synthesis

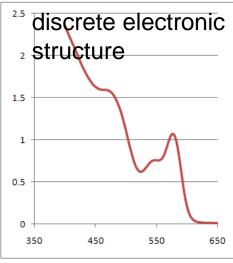


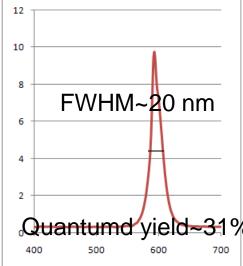
Nucleation Growth

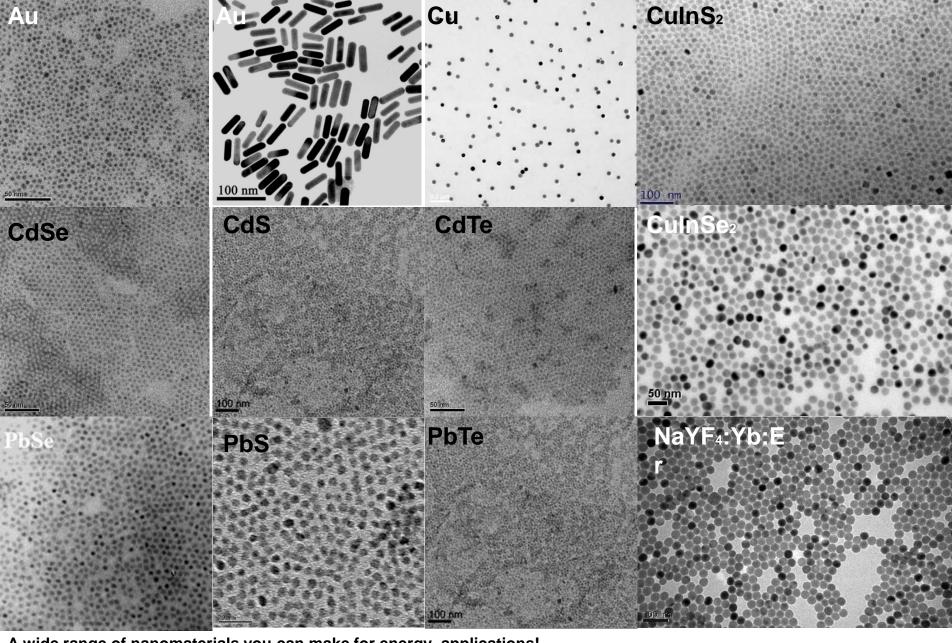
2 000



CdSe nanocrystals Average:4.69nm Size variation less Than 20%





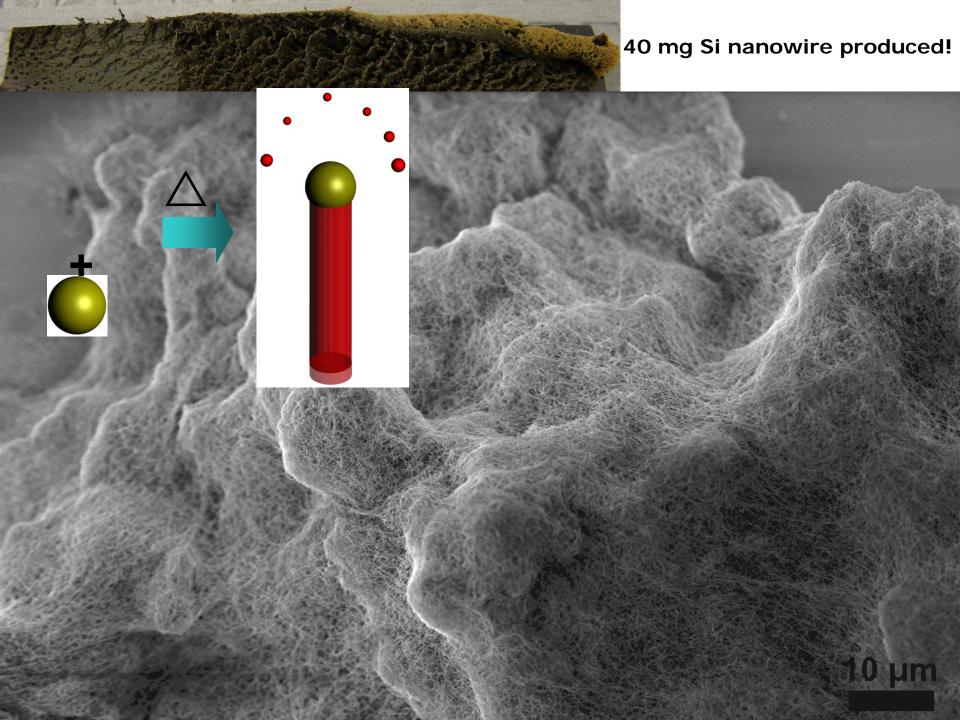


A wide range of nanomaterials you can make for energy applications!

Semiconductor nanocrystals: Cd chalcogenide; Pb chalcogenide; Cu-In- chalcogenide Metal nanostructures: gold and Cu

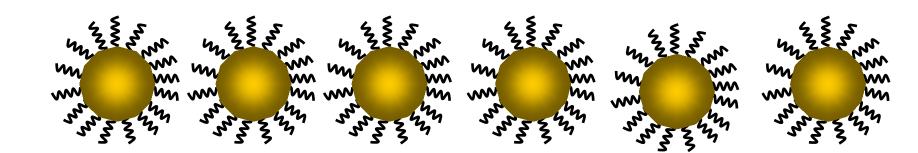
Upconversion nanocrystal: NaYF4: Yb: Er

段 et al. 未發表數據



Size Dependent optical properties f CdSe quantum dots
Plasmon absorption tuning of gold nanorods a/c Bright water-soluble CdSe/ZnS/CTAB quantum dots Quantum efficiency 40-60% CTAB 0.8 Extiction (a.u.) CdSe 400 450 500 550 600 650 700 750 800 850 900 950 ZnS Wayglength (ng). 未發表數據

CIGS nanocrystals as ink for thin film solar cell

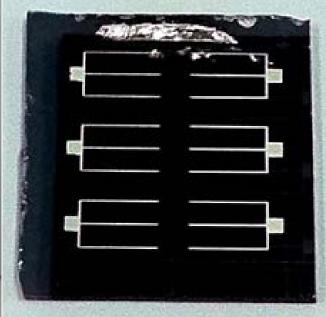


Why?

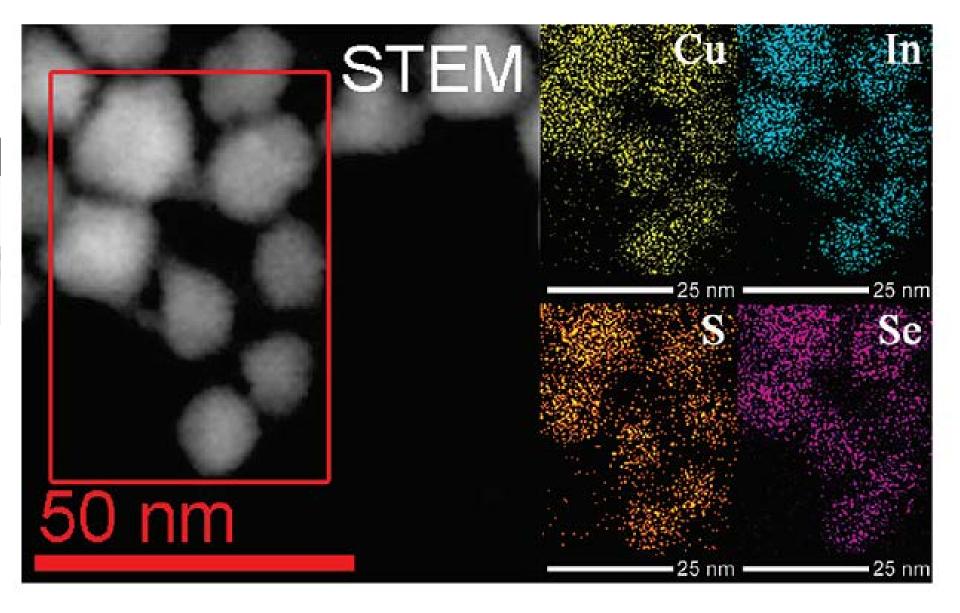
- -These nanocrystals are uniform size and composition and stable in solution
- -These nanocrystals could be easily accessible in solution-processing procedures, such as dip-coating, in-jet printing, drop-casting and could be implanted for future roll-to-roll fabrication processing.
- -These nanocrystals could be easily made in massive quantity using our proposed synthetic strategy.



Nanoparticle ink for CIGS solar cell

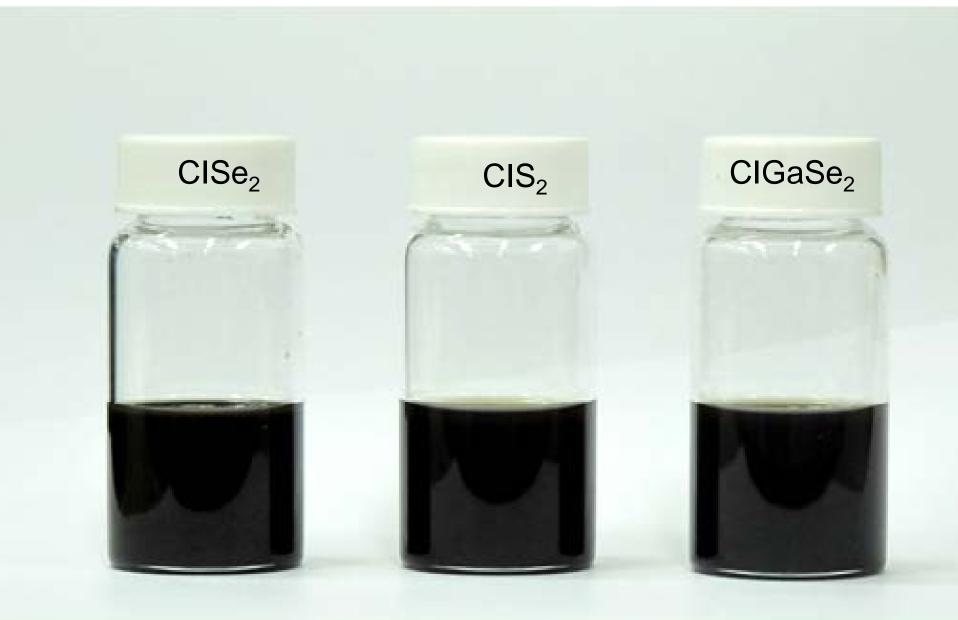


Culn(S_{0.5}Se_{0.5})₂ Nanoparticles

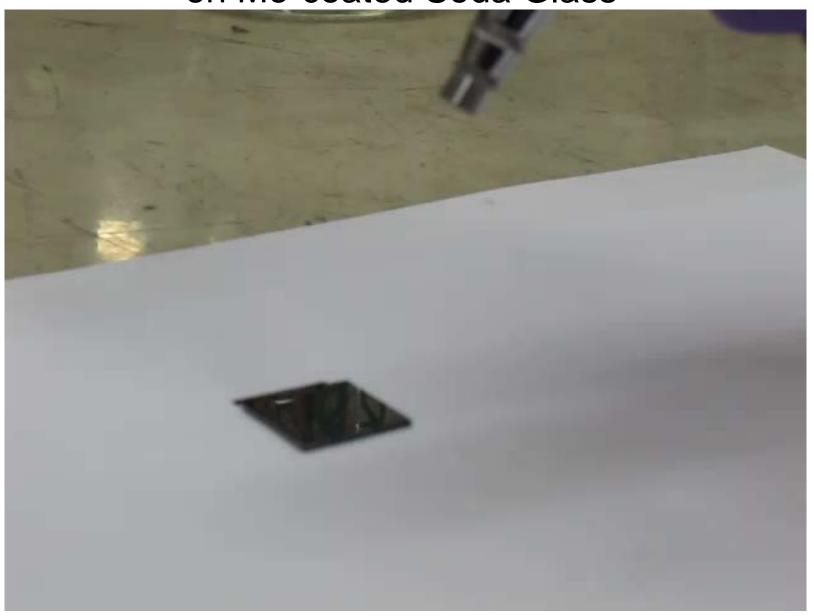




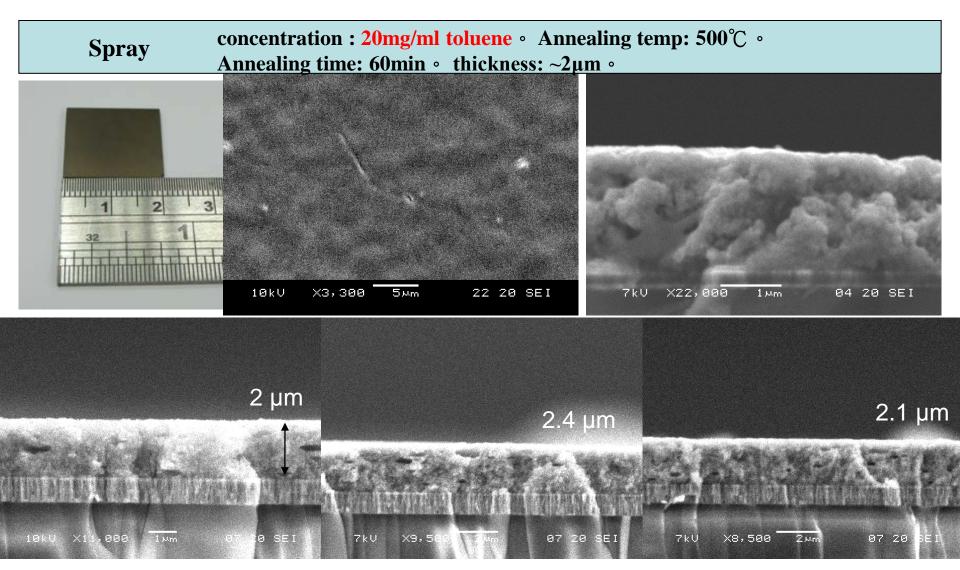
Photos of CIS₂, CISe₂, CIGS nanocrystal solution



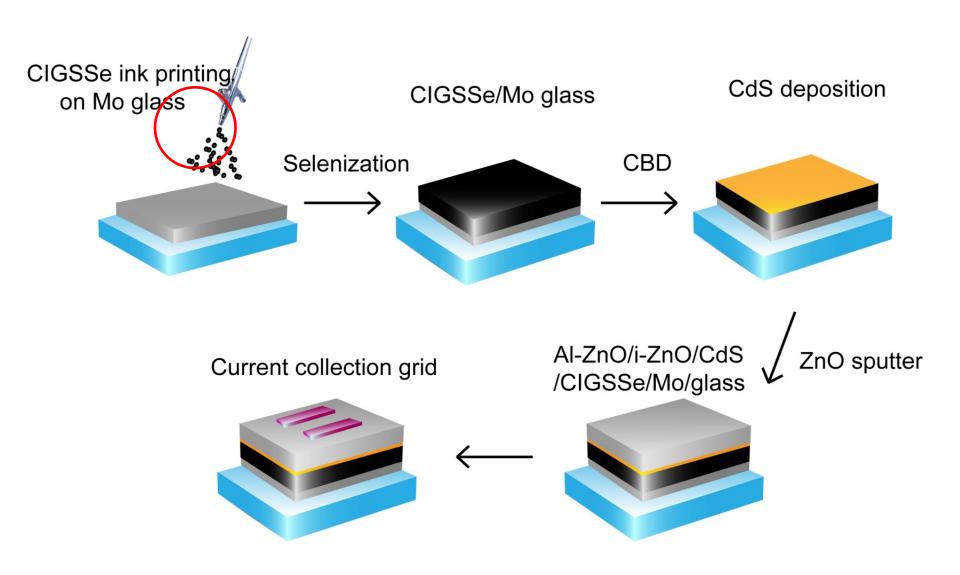
Spray-depositing Nanocrystals on Mo-coated Soda Glass



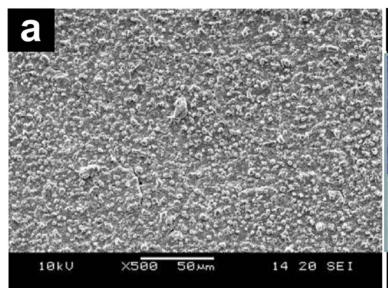
Spray-deposited Film

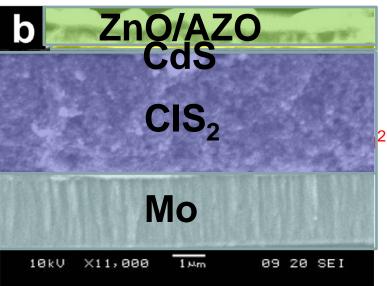


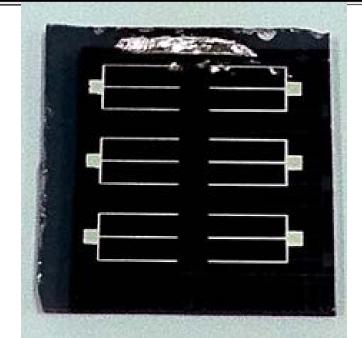
Procedure of CIGS photovoltaic device fabrication

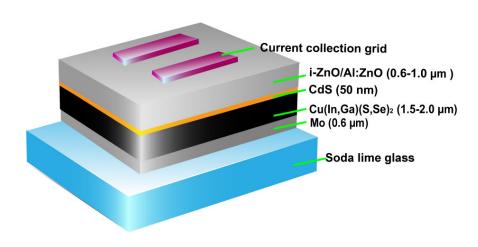


Final Device Efficiency

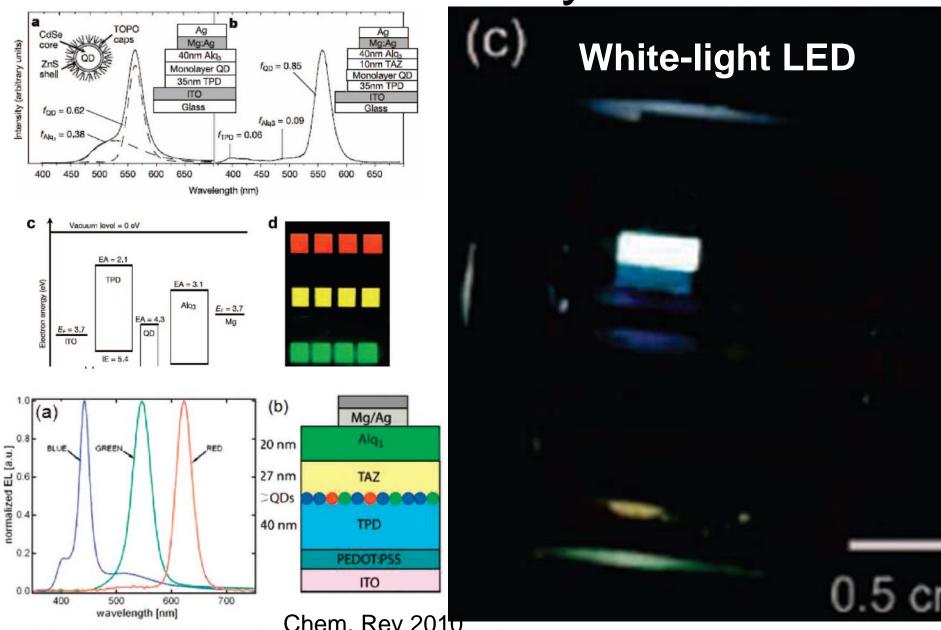




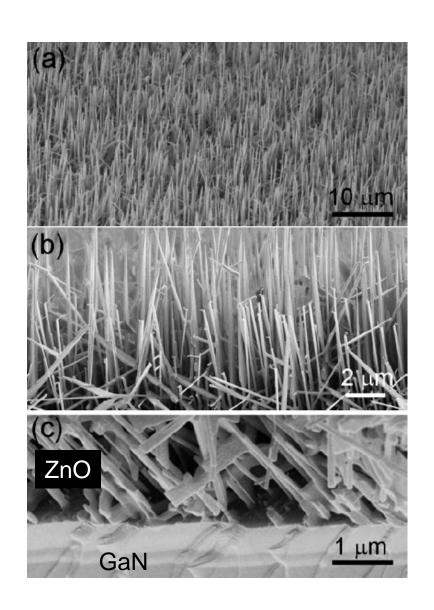


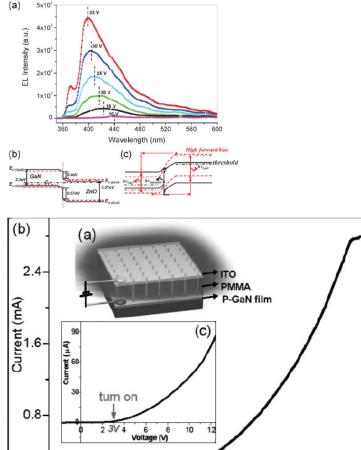


CdSe/ZnS nanocrystal LED



ZnO nanowire /GaN substrate LED





Zhang et al., Adv Mater., 2009

Voltage (V)

